



# CERTIFICATE OF ACCREDITATION

## ANSI-ASQ National Accreditation Board

500 Montgomery Street, Suite 625, Alexandria, VA 22314, 877-344-3044

This is to certify that

**Evans Analytical Group, LLC**  
**2710 Walsh Avenue**  
**Santa Clara, CA 95051**

has been assessed by ANAB  
and meets the requirements of international standard

## ISO/IEC 17025:2005

while demonstrating technical competence in the field of

## TESTING

Refer to the accompanying Scope of Accreditation for information regarding the types of tests to which this accreditation applies.

AT-1111  
Certificate Number

  
ANAB Approval

Certificate Valid: 06/28/2016-05/01/2017  
Version No. 002 Issued: 06/28/2016



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2005. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated January 2009).



# ANSI-ASQ National Accreditation Board

## SCOPE OF ACCREDITATION TO ISO/IEC 17025:2005

### Evans Analytical Group, LLC

2710 Walsh Avenue, Santa Clara, CA 95051  
 Robert Bruening Phone: 858-449-7485  
 rbruening@eag.com www.eaglabs.com

### TESTING

Valid to: May 1, 2017

Certificate Number: AT-1111

#### I. Electrical

Field of Test	Items, Materials or Products Tested	Specific Tests or Properties Measured	Specification, Standard Method, or Technique Used	Key Equipment or Technology*
Voltage Stress	Integrated Circuits	Rise / Fall Time 2 ns to 10 ns Rise / Decay Time 130 ns to 170 ns Current 0.15 A to 5.86 A	JEDEC JS-001 JESD22-A114 Mil Std 883 TM 3015.8 AEC-Q100-002 Test – Human Body Model	768 and 2304 Pin Capacity 100 V to 8 kV ThermoKeyTek MK2, MK4
		Frequency - 11 MHz to 16 MHz Current 1.5 A to 16.1 A	JEDEC JESD22-A115 AEC-Q100-003 Test – Machine Model	768 and 2304 Pin Capacity 50 V to 2 kV ThermoKeyTek MK2, MK4
		I-Test $V_{supply}$ Over-Voltage Test	JEDEC JESD78 AEC-Q100-004 Test –IC Latch-Up	768 and 2304 Pin Capacity 100 mA to 300 mA Temp 25 °C to 125 °C ThermoKeyTek MK2, MK4
		Rise / Fall Time < 400 ps Peak Current Magnitude 2.25 A to 18 A	JEDEC JESD22-C101 AEC-Q100-011 Test – Field Induced Charged Device Model	50 V to 2 kV ThermoKeyTek RCDM Discharge Plate



## II. Thermal

Field of Test	Items, Materials or Products Tested	Specific Tests or Properties Measured	Specification, Standard Method, or Technique Used	Key Equipment or Technology*
Environmental Stress	Integrated Circuits	HTOL (High Temperature Operating Life)	Mil Std. 883TM 1005.8, 1006, 1015 JESD22-A108	85 °C to 150 °C (1 to 20) V / (0 to 500) A
		HTSL (High Temperature Storage Life)	JESD22-A103	(100 to 185) °C
		THB (Temperature Humidity Bias)	JESD-A101	30 °C to 85 °C (60 to 95) %RH Non-Condensing
		PPOT – Pressure Pot	JESD22-A102	(121 to 135) °C, 20 PSI, 100 % Saturation
		HAST (Highly Accelerated Stress Test)	JESD22-A110	(110 to 145) °C, 35 PSI, 100 % Saturation @85 %RH (Max) Trio-tech HAST-6000X
		TMCL – Temperature Cycling	JESD22-A104 Mil Std. 883 TM 1010 Mil Std. 750 TM 1051	Condition A-N (air to air) (- 65 to 150) °C 10 min Dwell Instantaneous Ramp; 5 min Dwell 15 min Ramp
		Preconditioning	JESD22-A113	Level 1 ~ 6

**Notes:**

1. This scope is formatted as part of a single document including the Certificate of Accreditation No. AT-1111

  
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 Vice President